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Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

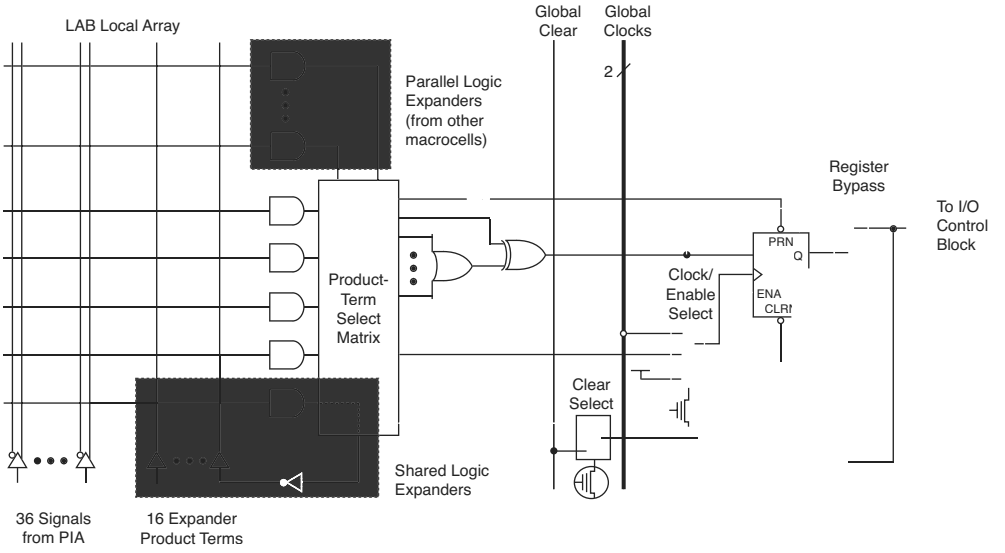
Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	32
Number of Macrocells	512
Number of Gates	10000
Number of I/O	172
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm3512aqc208-10n

Macrocells

MAX 3000A macrocells can be individually configured for either sequential or combinatorial logic operation. Macrocells consist of three functional blocks: logic array, product–term select matrix, and programmable register. Figure 2 shows a MAX 3000A macrocell.

Figure 2. MAX 3000A Macrocell



Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product–term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register preset, clock, and clock enable control functions.

Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The Altera development system automatically optimizes product–term allocation according to the logic requirements of the design.

For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the Altera development system software then selects the most efficient flipflop operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- Global clock signal mode, which achieves the fastest clock–to–output performance.
- Global clock signal enabled by an active–high clock enable. A clock enable is generated by a product term. This mode provides an enable on each flipflop while still achieving the fast clock–to–output performance of the global clock.
- Array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

Two global clock signals are available in MAX 3000A devices. As shown in Figure 1, these global clock signals can be the true or the complement of either of the two global clock pins, `GCLK1` or `GCLK2`.

Each register also supports asynchronous preset and clear functions. As shown in Figure 2, the product–term select matrix allocates product terms to control these operations. Although the product–term–driven preset and clear from the register are active high, active–low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the active–low dedicated global clear pin (`GCLRn`).

All registers are cleared upon power-up. By default, all registered outputs drive low when the device is powered up. You can set the registered outputs to drive high upon power-up through the Quartus® II software. Quartus II software uses the NOT Gate Push-Back method, which uses an additional macrocell to set the output high. To set this in the Quartus II software, go to the Assignment Editor and set the **Power-Up Level** assignment for the register to **High**.

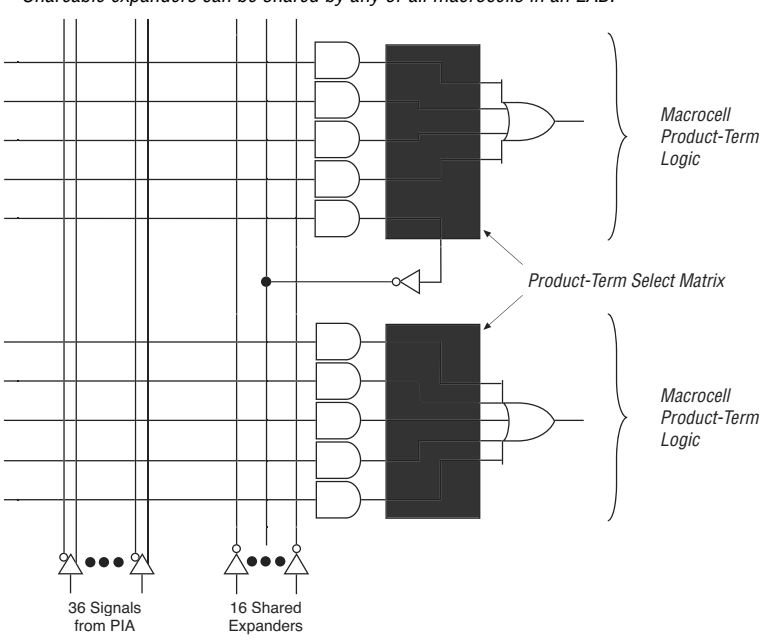
Expander Product Terms

Although most logic functions can be implemented with the five product terms available in each macrocell, highly complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 3000A architecture also offers both shareable and parallel expander product terms ("expanders") that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. Shareable expanders incur a small delay (t_{SEXP}). Figure 3 shows how shareable expanders can feed multiple macrocells.

Figure 3. MAX 3000A Shareable Expanders



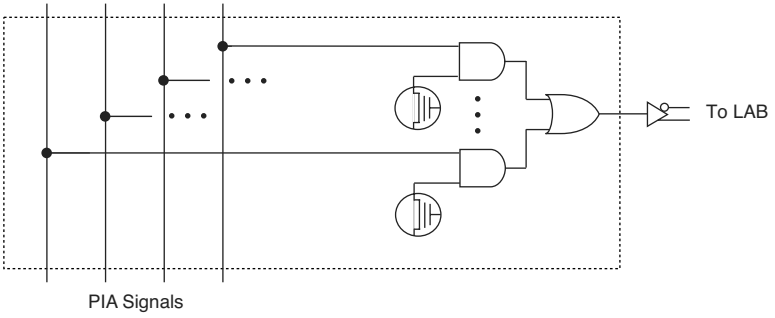
Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The Altera development system compiler can automatically allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay (t_{PEXP}). For example, if a macrocell requires 14 product terms, the compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms, and the second set includes four product terms, increasing the total delay by $2 \times t_{PEXP}$.

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower–numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest–numbered macrocell can only lend parallel expanders and the highest–numbered macrocell can only borrow them. Figure 4 shows how parallel expanders can be borrowed from a neighboring macrocell.

Figure 5. MAX 3000A PIA Routing

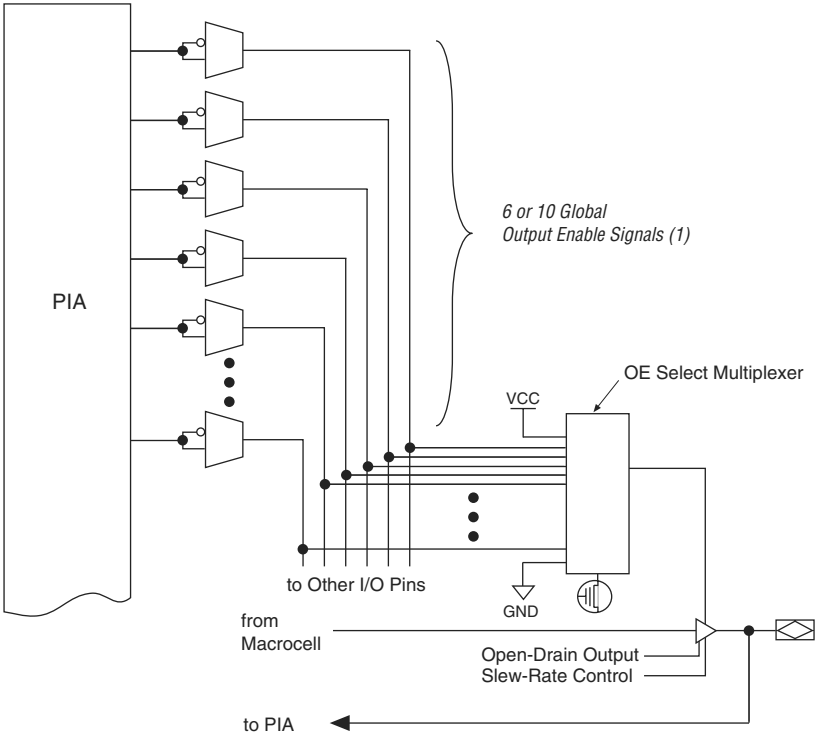


While the routing delays of channel–based routing schemes in masked or FPGAs are cumulative, variable, and path–dependent, the MAX 3000A PIA has a predictable delay. The PIA makes a design's timing performance easy to predict.

I/O Control Blocks

The I/O control block allows each I/O pin to be individually configured for input, output, or bidirectional operation. All I/O pins have a tri–state buffer that is individually controlled by one of the global output enable signals or directly connected to ground or V_{CC}. Figure 6 shows the I/O control block for MAX 3000A devices. The I/O control block has 6 or 10 global output enable signals that are driven by the true or complement of two output enable signals, a subset of the I/O pins, or a subset of the I/O macrocells.

Figure 6. I/O Control Block of MAX 3000A Devices



Note:
(1) EPM3032A, EPM3064A, EPM3128A, and EPM3256A devices have six output enables. EPM3512A devices have 10 output enables.

When the tri–state buffer control is connected to ground, the output is tri-stated (high impedance), and the I/O pin can be used as a dedicated input. When the tri–state buffer control is connected to V_{CC}, the output is enabled.

The MAX 3000A architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

In–System Programmability

MAX 3000A devices can be programmed in–system via an industry–standard four–pin IEEE Std. 1149.1-1990 (JTAG) interface. In-system programmability (ISP) offers quick, efficient iterations during design development and debugging cycles. The MAX 3000A architecture internally generates the high programming voltages required to program its EEPROM cells, allowing in–system programming with only a single 3.3–V power supply. During in–system programming, the I/O pins are tri–stated and weakly pulled–up to eliminate board conflicts. The pull–up value is nominally 50 kΩ

MAX 3000A devices have an enhanced ISP algorithm for faster programming. These devices also offer an `ISP_Done` bit that ensures safe operation when in–system programming is interrupted. This `ISP_Done` bit, which is the last bit programmed, prevents all I/O pins from driving until the bit is programmed.

ISP simplifies the manufacturing flow by allowing devices to be mounted on a printed circuit board (PCB) with standard pick–and–place equipment before they are programmed. MAX 3000A devices can be programmed by downloading the information via in–circuit testers, embedded processors, the MasterBlaster communications cable, the ByteBlasterMV parallel port download cable, and the BitBlaster serial download cable. Programming the devices after they are placed on the board eliminates lead damage on high–pin–count packages (e.g., QFP packages) due to device handling. MAX 3000A devices can be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

The Jam STAPL programming and test language can be used to program MAX 3000A devices with in–circuit testers, PCs, or embedded processors.

For more information on using the Jam STAPL programming and test language, see *Application Note 88 (Using the Jam Language for ISP & ICR via an Embedded Processor)*, *Application Note 122 (Using Jam STAPL for ISP & ICR via an Embedded Processor)* and *AN 111 (Embedded Programming Using the 8051 and Jam Byte-Code)*.

The ISP circuitry in MAX 3000A devices is compliant with the IEEE Std. 1532 specification. The IEEE Std. 1532 is a standard developed to allow concurrent ISP between multiple PLD vendors.

By combining the pulse and shift times for each of the programming stages, the program or verify time can be derived as a function of the TCK frequency, the number of devices, and specific target device(s). Because different ISP-capable devices have a different number of EEPROM cells, both the total fixed and total variable times are unique for a single device.

Programming a Single MAX 3000A Device

The time required to program a single MAX 3000A device in-system can be calculated from the following formula:

$$t_{PROG} = t_{PPULSE} + \frac{Cycle_{PTCK}}{f_{TCK}}$$

where: t_{PROG} = Programming time
t_{PPULSE} = Sum of the fixed times to erase, program, and verify the EEPROM cells
$Cycle_{PTCK}$ = Number of TCK cycles to program a device
f_{TCK} = TCK frequency

The ISP times for a stand-alone verification of a single MAX 3000A device can be calculated from the following formula:

$$t_{VER} = t_{VPULSE} + \frac{Cycle_{VTCK}}{f_{TCK}}$$

where: t_{VER} = Verify time
t_{VPULSE} = Sum of the fixed times to verify the EEPROM cells
$Cycle_{VTCK}$ = Number of TCK cycles to verify a device

Programmable Speed/Power Control

MAX 3000A devices offer a power–saving mode that supports low-power operation across user–defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 3000A device for either high–speed or low–power operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the t_{LAD}, t_{LAC}, t_{IC}, t_{ACL}, t_{EN}, t_{CPPW} and t_{SEXP} parameters.

Output Configuration

MAX 3000A device outputs can be programmed to meet a variety of system–level requirements.

MultiVolt I/O Interface

The MAX 3000A device architecture supports the MultiVolt I/O interface feature, which allows MAX 3000A devices to connect to systems with differing supply voltages. MAX 3000A devices in all packages can be set for 2.5–V, 3.3–V, or 5.0–V I/O pin operation. These devices have one set of V_{CC} pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The VCCIO pins can be connected to either a 3.3–V or 2.5–V power supply, depending on the output requirements. When the VCCIO pins are connected to a 2.5–V power supply, the output levels are compatible with 2.5–V systems. When the VCCIO pins are connected to a 3.3–V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0–V systems. Devices operating with V_{CCIO} levels lower than 3.0 V incur a nominally greater timing delay of t_{OD2} instead of t_{OD1}. Inputs can always be driven by 2.5–V, 3.3–V, or 5.0–V signals.

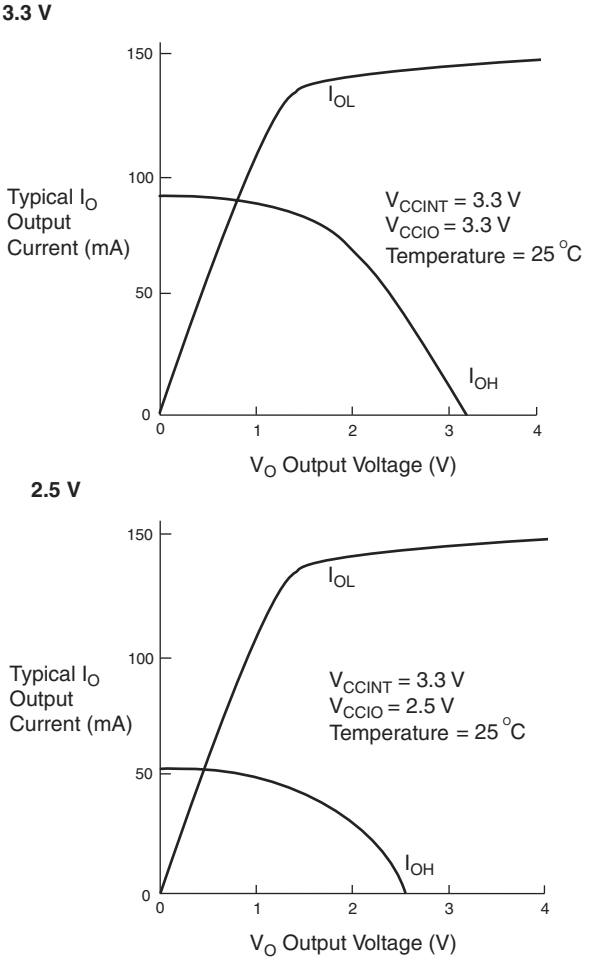
Table 11 summarizes the MAX 3000A MultiVolt I/O support.

Table 11. MAX 3000A MultiVolt I/O Support

V_{CCIO} Voltage	Input Signal (V)			Output Signal (V)		
	2.5	3.3	5.0	2.5	3.3	5.0
2.5	✓	✓	✓	✓		
3.3	✓	✓	✓	✓	✓	✓

Note:
(1) When V_{CCIO} is 3.3 V, a MAX 3000A device can drive a 2.5–V device that has 3.3–V tolerant inputs.

Figure 9. Output Drive Characteristics of MAX 3000A Devices



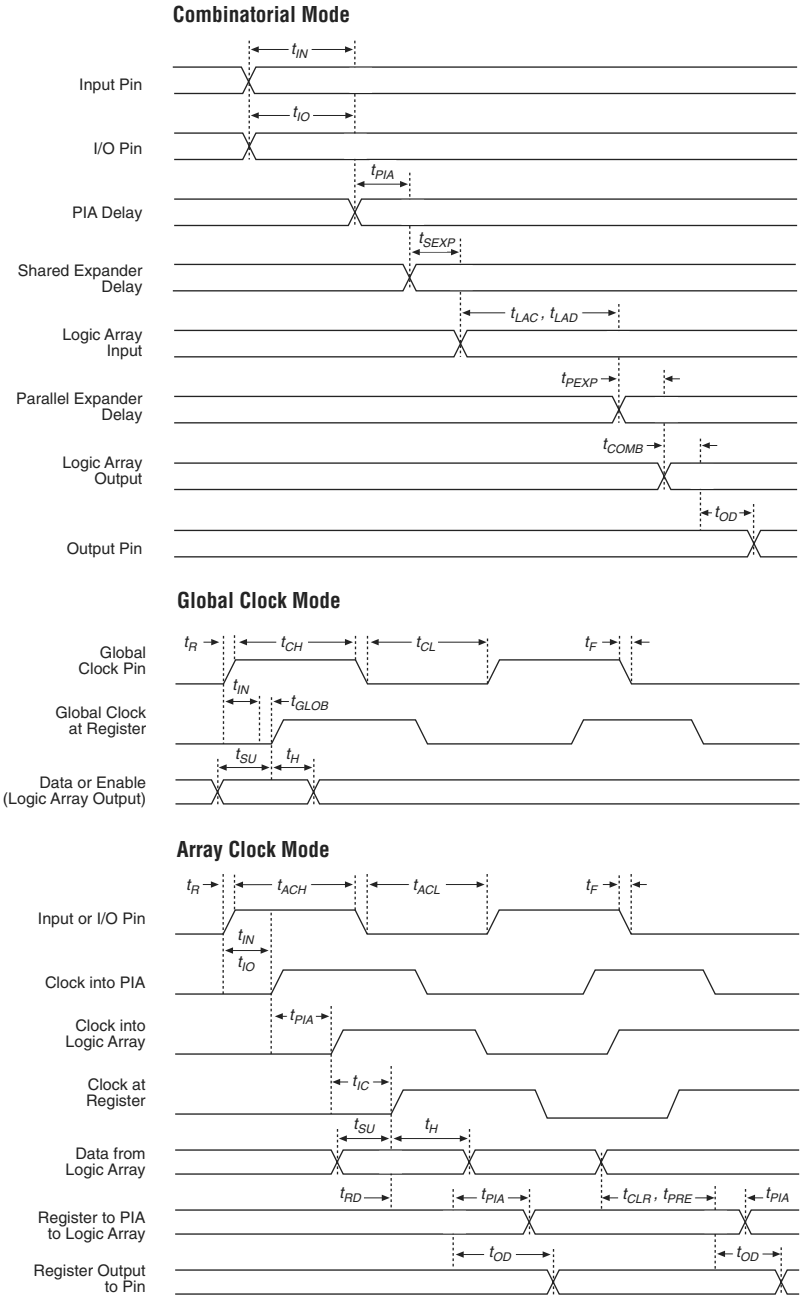
Power Sequencing & Hot–Socketing

Because MAX 3000A devices can be used in a mixed–voltage environment, they have been designed specifically to tolerate any possible power–up sequence. The V_{CCIO} and V_{CCINT} power planes can be powered in any order.

Signals can be driven into MAX 3000A devices before and during power-up without damaging the device. In addition, MAX 3000A devices do not drive out during power-up. Once operating conditions are reached, MAX 3000A devices operate as specified by the user.

Figure 11. MAX 3000A Switching Waveforms

t_R & t_F < 2 ns. Inputs are driven at 3 V for a logic high and 0 V for a logic low. All timing characteristics are measured at 1.5 V.



Tables 16 through 23 show EPM3032A, EPM3064A, EPM3128A, EPM3256A, and EPM3512A timing information.

Table 16. EPM3032A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–4		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{PD1}	Input to non–registered output	C1 = 35 pF *(2)*		4.5		7.5		10	ns
t_{PD2}	I/O input to non–registered output	C1 = 35 pF *(2)*		4.5		7.5		10	ns
t_{SU}	Global clock setup time	*(2)*	2.9		4.7		6.3		ns
t_{H}	Global clock hold time	*(2)*	0.0		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.0	1.0	5.0	1.0	6.7	ns
t_{CH}	Global clock high time		2.0		3.0		4.0		ns
t_{CL}	Global clock low time		2.0		3.0		4.0		ns
t_{ASU}	Array clock setup time	*(2)*	1.6		2.5		3.6		ns
t_{AH}	Array clock hold time	*(2)*	0.3		0.5		0.5		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF *(2)*	1.0	4.3	1.0	7.2	1.0	9.4	ns
t_{ACH}	Array clock high time		2.0		3.0		4.0		ns
t_{ACL}	Array clock low time		2.0		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(3)*	2.0		3.0		4.0		ns
t_{CNT}	Minimum global clock period	*(2)*		4.4		7.2		9.7	ns
f_{CNT}	Maximum internal global clock frequency	*(2)*, *(4)*	227.3		138.9		103.1		MHz
t_{ACNT}	Minimum array clock period	*(2)*		4.4		7.2		9.7	ns
f_{ACNT}	Maximum internal array clock frequency	*(2)*, *(4)*	227.3		138.9		103.1		MHz

Table 19. EPM3064A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–4		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{CLR}	Register clear time			1.3		2.1		2.9	ns
t_{PIA}	PIA delay	*(2)*		1.0		1.7		2.3	ns
t_{LPA}	Low–power adder	*(5)*		3.5		4.0		5.0	ns

Table 20. EPM3128A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–5		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{PD1}	Input to non–registered output	C1 = 35 pF *(2)*		5.0		7.5		10	ns
t_{PD2}	I/O input to non–registered output	C1 = 35 pF *(2)*		5.0		7.5		10	ns
t_{SU}	Global clock setup time	*(2)*	3.3		4.9		6.6		ns
t_{H}	Global clock hold time	*(2)*	0.0		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.4	1.0	5.0	1.0	6.6	ns
t_{CH}	Global clock high time		2.0		3.0		4.0		ns
t_{CL}	Global clock low time		2.0		3.0		4.0		ns
t_{ASU}	Array clock setup time	*(2)*	1.8		2.8		3.8		ns
t_{AH}	Array clock hold time	*(2)*	0.2		0.3		0.4		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF *(2)*	1.0	4.9	1.0	7.1	1.0	9.4	ns
t_{ACH}	Array clock high time		2.0		3.0		4.0		ns
t_{ACL}	Array clock low time		2.0		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(3)*	2.0		3.0		4.0		ns
t_{CNT}	Minimum global clock period	*(2)*		5.2		7.7		10.2	ns
f_{CNT}	Maximum internal global clock frequency	*(2)*, *(4)*	192.3		129.9		98.0		MHz
t_{ACNT}	Minimum array clock period	*(2)*		5.2		7.7		10.2	ns

Table 20. EPM3128A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–5		–7		–10		
			Min	Max	Min	Max	Min	Max	
f_{ACNT}	Maximum internal array clock frequency	*(2), (4)*	192.3		129.9		98.0		MHz

Table 21. EPM3128A Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–5		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.7		1.0		1.4	ns
t_{IO}	I/O input pad and buffer delay			0.7		1.0		1.4	ns
t_{SEXP}	Shared expander delay			2.0		2.9		3.8	ns
t_{PEXP}	Parallel expander delay			0.4		0.7		0.9	ns
t_{LAD}	Logic array delay			1.6		2.4		3.1	ns
t_{LAC}	Logic control array delay			0.7		1.0		1.3	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		0.8		1.2		1.6	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		1.3		1.7		2.1	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		5.8		6.2		6.6	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0	ns

Table 21. EPM3128A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–5		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{SU}	Register setup time		1.4		2.1		2.9		ns
t_{H}	Register hold time		0.6		1.0		1.3		ns
t_{RD}	Register delay			0.8		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.5		0.9		1.3	ns
t_{IC}	Array clock delay			1.2		1.7		2.2	ns
t_{EN}	Register enable time			0.7		1.0		1.3	ns
t_{GLOB}	Global control delay			1.1		1.6		2.0	ns
t_{PRE}	Register preset time			1.4		2.0		2.7	ns
t_{CLR}	Register clear time			1.4		2.0		2.7	ns
t_{PIA}	PIA delay	*(2)*		1.4		2.0		2.6	ns
t_{LPA}	Low–power adder	*(5)*		4.0		4.0		5.0	ns

Table 22. EPM3256A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			–7		–10		
			Min	Max	Min	Max	
t_{PD1}	Input to non–registered output	C1 = 35 pF *(2)*		7.5		10	ns
t_{PD2}	I/O input to non–registered output	C1 = 35 pF *(2)*		7.5		10	ns
t_{SU}	Global clock setup time	*(2)*	5.2		6.9		ns
t_{H}	Global clock hold time	*(2)*	0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	4.8	1.0	6.4	ns
t_{CH}	Global clock high time		3.0		4.0		ns
t_{CL}	Global clock low time		3.0		4.0		ns
t_{ASU}	Array clock setup time	*(2)*	2.7		3.6		ns
t_{AH}	Array clock hold time	*(2)*	0.3		0.5		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF *(2)*	1.0	7.3	1.0	9.7	ns
t_{ACH}	Array clock high time		3.0		4.0		ns
t_{ACL}	Array clock low time		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(3)*	3.0		4.0		ns

Table 22. EPM3256A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			–7		–10		
			Min	Max	Min	Max	
t_{CNT}	Minimum global clock period	*(2)*		7.9		10.5	ns
f_{CNT}	Maximum internal global clock frequency	*(2)*, *(4)*	126.6		95.2		MHz
t_{ACNT}	Minimum array clock period	*(2)*		7.9		10.5	ns
f_{ACNT}	Maximum internal array clock frequency	*(2)*, *(4)*	126.6		95.2		MHz

Table 23. EPM3256A Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			–7		–10		
			Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.9		1.2	ns
t_{IO}	I/O input pad and buffer delay			0.9		1.2	ns
t_{SEXP}	Shared expander delay			2.8		3.7	ns
t_{PEXP}	Parallel expander delay			0.5		0.6	ns
t_{LAD}	Logic array delay			2.2		2.8	ns
t_{LAC}	Logic control array delay			1.0		1.3	ns
t_{IOE}	Internal output enable delay			0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		1.2		1.6	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		1.7		2.1	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		6.2		6.6	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		4.5		5.5	ns

Table 23. EPM3256A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			–7		–10		
			Min	Max	Min	Max	
t_{ZX3}	Output buffer enable delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		5.0	ns
t_{SU}	Register setup time		2.1		2.9		ns
t_{H}	Register hold time		0.9		1.2		ns
t_{RD}	Register delay			1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.8		1.2	ns
t_{IC}	Array clock delay			1.6		2.1	ns
t_{EN}	Register enable time			1.0		1.3	ns
t_{GLOB}	Global control delay			1.5		2.0	ns
t_{PRE}	Register preset time			2.3		3.0	ns
t_{CLR}	Register clear time			2.3		3.0	ns
t_{PIA}	PIA delay	*(2)*		2.4		3.2	ns
t_{LPA}	Low–power adder	*(5)*		4.0		5.0	ns

Table 24. EPM3512A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			-7		-10		
			Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF *(2)*		7.5		10.0	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF *(2)*		7.5		10.0	ns
t_{SU}	Global clock setup time	*(2)*	5.6		7.6		ns
t_{H}	Global clock hold time	*(2)*	0.0		0.0		ns
t_{FSU}	Global clock setup time of fast input		3.0		3.0		ns
t_{FH}	Global clock hold time of fast input		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	4.7	1.0	6.3	ns
t_{CH}	Global clock high time		3.0		4.0		ns
t_{CL}	Global clock low time		3.0		4.0		ns
t_{ASU}	Array clock setup time	*(2)*	2.5		3.5		ns

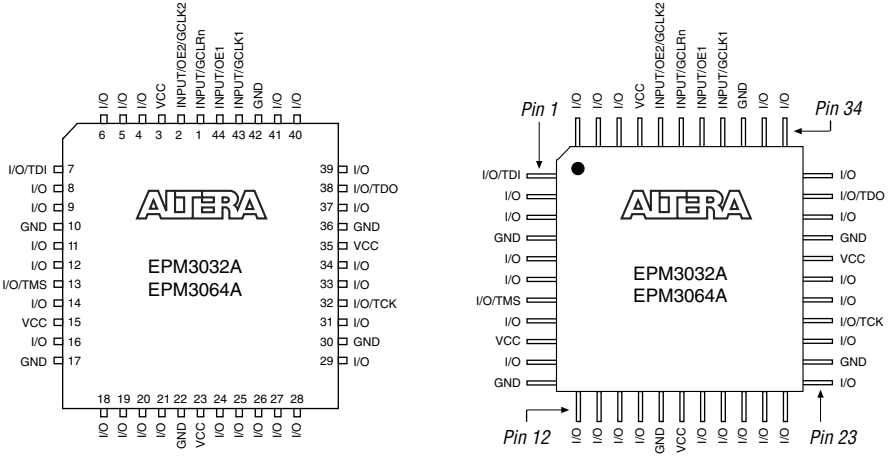
Device Pin–Outs

See the Altera web site (**http://www.altera.com**) or the *Altera Digital Library* for pin–out information.

Figures 14 through 18 show the package pin–out diagrams for MAX 3000A devices.

Figure 14. 44–Pin PLCC/TQFP Package Pin–Out Diagram

Package outlines not drawn to scale.



44-Pin PLCC

44-Pin TQFP

Figure 15. 100–Pin TQFP Package Pin–Out Diagram

Package outline not drawn to scale.

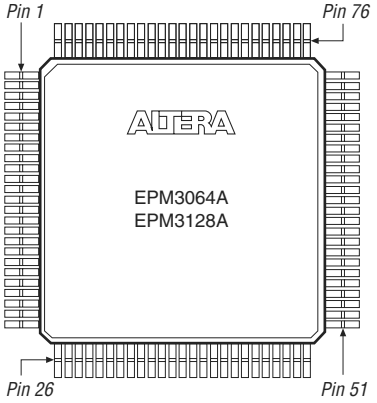
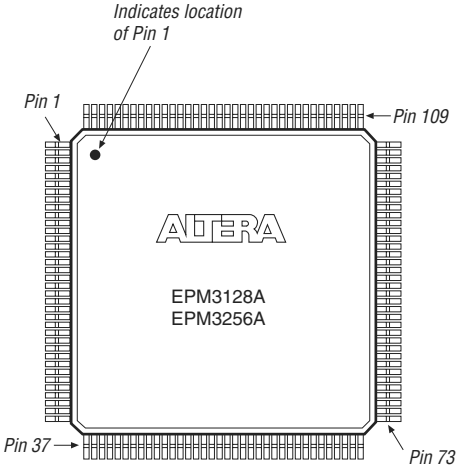


Figure 16. 144–Pin TQFP Package Pin–Out Diagram

Package outline not drawn to scale.



Version 3.3

The following changes were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.3:

- Updated Tables 3, 13, and 26.
- Added Tables 4 through 6.
- Updated Figures 12 and 13.
- Added "Programming Sequence" on page 14 and "Programming Times" on page 14

Version 3.2

The following change were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.2:

- Updated the EPM3512 I_{CC} versus frequency graph in Figure 13.

Version 3.1

The following changes were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.1:

- Updated timing information in Table 1 for the EPM3256A device.
- Updated *Note (10)* of Table 15.

Version 3.0

The following changes were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.0:

- Added EPM3512A device.
- Updated Tables 2 and 3.

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